

**Notice of References Cited**

Application/Control No.

09/865,564

Applicant(s)/Patent Under  
Reexamination  
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Examiner

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Art Unit

2823

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-US006300191B1	10-01	Yu et al.	
	B	US-US006169304B1	01-2002	Arita et al.	
	C	US-5759903	06-1998	Lehmann et al.	
	D	US-US006153460A	11-2000	Ohnishi et al.	
	E	US-US006388281B1	05-2002	Jung et al.	
	F	US-US006359295B2	03-2002	Lee et al.	
	G	US-5631185	05-1997	Kim et al.	
	H	US-US006261901B1	07-01	Tseng	
	I	US-US006255224B1	07-01	Kim	
	J	US-US006239022B1	05-2001	Seo et al.	
	K	US-US006136695A	10-2000	Lee et al.	
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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